

**April 2009** 

# FDP054N10

# N-Channel PowerTrench<sup>®</sup> MOSFET 100V, 144A, $5.5m\Omega$

### **Features**

- $R_{DS(on)} = 4.6 \text{m}\Omega$  ( Typ.)@  $V_{GS} = 10 \text{V}$ ,  $I_D = 75 \text{A}$
- · Fast Switching Speed
- · Low Gate Charge
- High Performance Trench Technology for Extremely Low  $R_{\mbox{\footnotesize{DS(on)}}}$
- · High Power and Current Handling Capability
- · RoHS Compliant

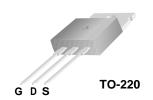


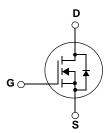
# **Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

# **Application**

DC to DC Converters / Synchronous Rectification





# **MOSFET Maximum Ratings** T<sub>C</sub> = 25°C unless otherwise noted

Symbol		Parameter		Ratings	Units
V <sub>DSS</sub>	Drain to Source Voltage	Drain to Source Voltage			V
V <sub>GSS</sub>	Gate to Source Voltage			±20	V
		- Continuous (T <sub>C</sub> = 25°C, Silic	con Limited)	144*	
$I_D$	Drain Current	- Continuous (T <sub>C</sub> = 100°C, Sil	icon Limited)	102	Α
		- Continuous (T <sub>C</sub> = 25°C, Pac	kage Limited)	120	
$I_{DM}$	Drain Current	- Pulsed	(Note 1)	576	А
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		(Note 2)	1153	mJ
dv/dt	Peak Diode Avalanche Energy (Note 3)		(Note 3)	3.6	V/ns
П	Dawar Dissination	$(T_C = 25^{\circ}C)$		263	W
$P_{D}$	Power Dissipation	- Derate above 25°C		1.75	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Te	perating and Storage Temperature Range			°C
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C

<sup>\*</sup>Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 120A.

# **Thermal Characteristics**

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.57	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	Resistance, Junction to Ambient 62.5	

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP054N10	FDP054N10	TO-220	-	-	50

# **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter Test Conditions		Min.	Тур.	Max.	Units
Off Charac	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A$ , $V_{GS} = 0 V$ , $T_C = 25 ^{\circ} C$	100	-	-	V
$\Delta BV_{DSS} \over \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , Referenced to $25^{\circ}\text{C}$	-	0.01	-	V/°C
1	Zoro Coto Voltago Proin Current	V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V	-	-	1	μА
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 100V, V_{GS} = 0V, T_{C} = 150^{\circ}C$	-	-	500	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA

#### On Characteristics

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.5	3.5	4.5	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 75A$	-	4.6	5.5	mΩ
9 <sub>FS</sub>	Forward Transconductance	$V_{GS} = 10V, I_D = 75A$ (Note 4)	-	192	-	S

# **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 05V V 0V		9985	13280	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V f = 1MHz	-	935	1245	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 11/11/2	-	390	585	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V	V 00V 1 754	-	156	203	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DS} = 80V, I_{D} = 75A,$ $V_{GS} = 10V$	-	53	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	(Note 4,5	-	48	-	nC

# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time	V 50V L 75A	-	44	98	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 50V, I_{D} = 75A$ $V_{GS} = 10V, R_{GEN} = 4.7\Omega$	-	92	194	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	VGS = 10V, NGEN = 4.752	-	80	170	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4,5)	-	39	88	ns

#### **Drain-Source Diode Characteristics**

IS	Maximum Continuous Drain to Source Diode Forward Current			ı	-	144	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	-	576	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 75A$		-	-	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> =75A		-	57	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	(Note 4)	-	121	-	nC

- 1: Repetitive Rating: Pulse width limited by maximum junction temperature 2: L = 0.41 mJ,  $I_{AS}$  = 75A,  $V_{DD}$  = 50V,  $R_{G}$  = 250, Starting  $T_{J}$  = 25°C 3:  $I_{SD}$  ≤ 75A, di'dt' ≤ 200A/µs,  $V_{DD}$  ≤  $BV_{DSS}$ , Starting  $T_{J}$  = 25°C 4: Pulse Test: Pulse width ≤ 300µs, Duty Cycle ≤ 2% 5: Essentially Independent of Operating Temperature Typical Characteristics

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

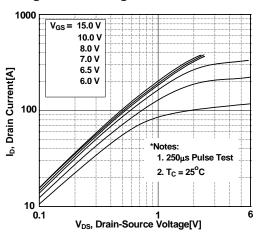


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

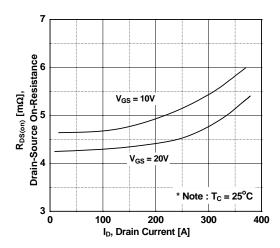


Figure 5. Capacitance Characteristics

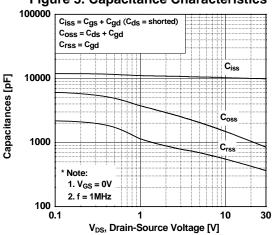


Figure 2. Transfer Characteristics

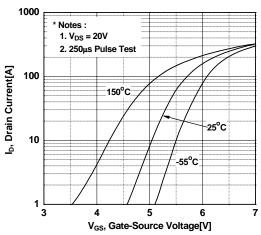


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

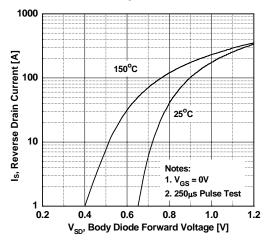
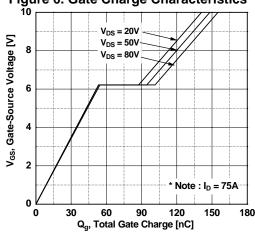


Figure 6. Gate Charge Characteristics



# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

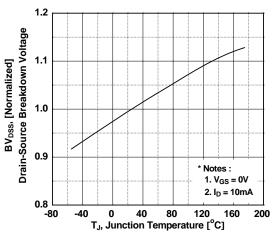


Figure 9. Maximum Safe Operating Area

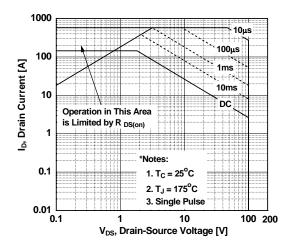


Figure 8. On-Resistance Variation vs. Temperature

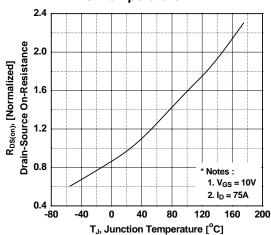


Figure 10. Maximum Drain Current vs. Case Temperature

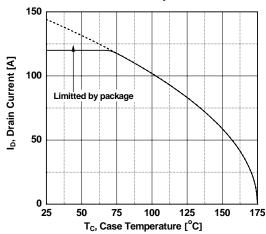
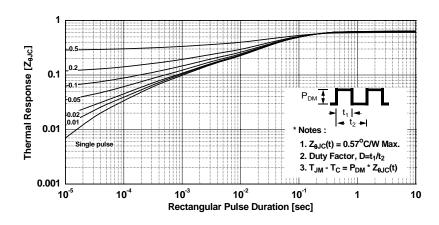
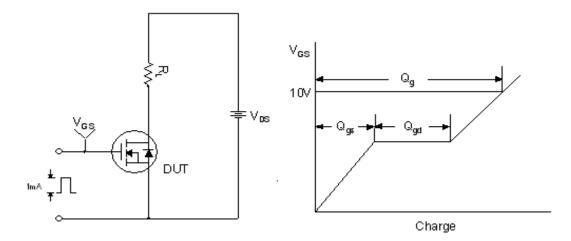


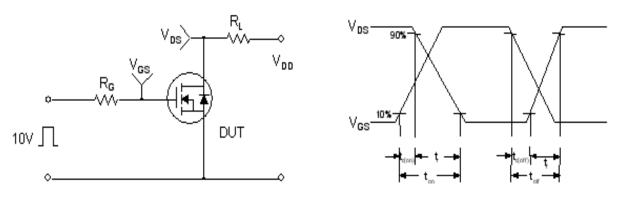
Figure 11. Transient Thermal Response Curve



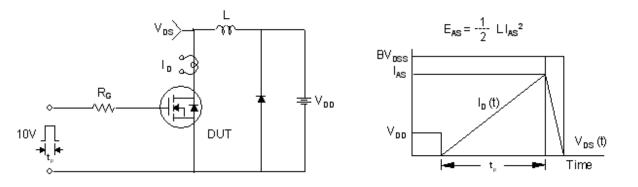
# **Gate Charge Test Circuit & Waveform**



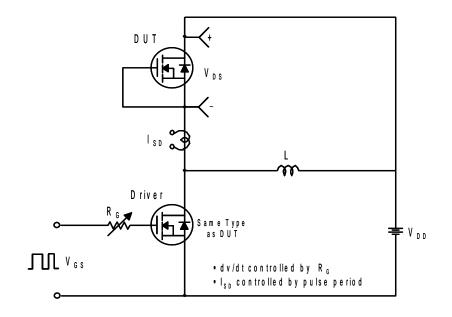
# **Resistive Switching Test Circuit & Waveforms**

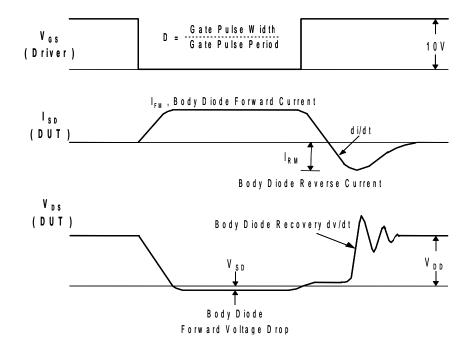


# **Unclamped Inductive Switching Test Circuit & Waveforms**



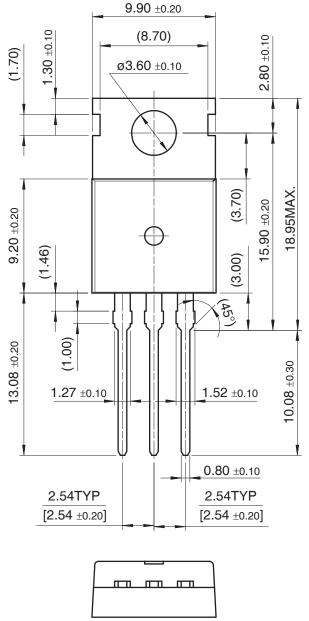
#### Peak Diode Recovery dv/dt Test Circuit & Waveforms

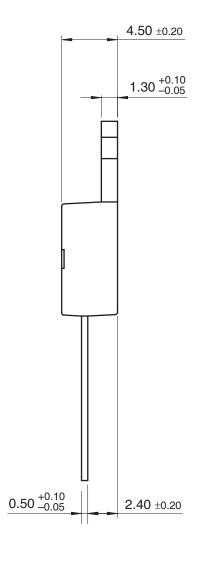




# **Mechanical Dimensions**

TO-220











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Rev. 140